# Samwin®

N-channel Enhanced mode SOP8 MOSFET

Features

- High ruggedness
- Low $R_{DS(ON)}$ (Typ 12mΩ)@V_{GS}=4.5V
  (Typ 9.5mΩ)@V_{GS}=10V
- Low Gate Charge (Typ 18nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application:Synchronous Rectification,
  Li Battery Protect Board, Inverter

SOP8

4. Gate 5,6,7,8.Drain 1,2,3.Source

BV_{DSS} : 60V

I_D : 10A

$R_{DS(ON)}$: 12mΩ@VGS=4.5V

9.5mΩ@VGS=10V

General Description

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.

Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW K 083R06VSM	083R06VSM	SOP8	REEL

Absolute maximum ratings
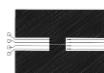
Symbol	Parameter		Value	Unit
V_{DSS}	Drain to source voltage		60	V
I_D	Continuous drain current (@T_a=25ºC)		10*	A
	Continuous drain current (@T_a=70ºC)		9*	A
I_{DM}	Drain current pulsed	(note 1)	40	A
V_{GS}	Gate to source voltage		±20	V
E_{AS}	Single pulsed avalanche energy	(note 2)	95	mJ
E_{AR}	Repetitive avalanche energy	(note 1)	9	mJ
dv/dt	Peak diode recovery dv/dt	(note 3)	5	V/ns
P_D	Total power dissipation (@T_a=25ºC)		2.4	W
	Derating factor above 25ºC		0.02	W/ºC
T_{STG}, T_J	Operating junction temperature & storage temperature		-55 ~ + 150	ºC

*. Drain current is limited by junction temperature.

Thermal characteristics

Symbol	Parameter	Value	Unit
R_{thja}	Thermal resistance, Junction to ambient	52.4	ºC/W

Note: R_{thja} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{thjc} is guaranteed by design while R_{thca} is determined by the user's board design.

SOP-8 R_{thja} : 52.4ºC/W on a 1 in² pad of 2oz copper.

Electrical characteristic (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
Off characteristics						
BV_{DSS}	Drain to source breakdown voltage	V_{GS}=0V, I_D=250uA	60			V
ΔBV_{DSS} / ΔT_J	Breakdown voltage temperature coefficient	I_D=250uA, referenced to 25°C		0.03		V/°C
I_{DSS}	Drain to source leakage current	V_{DS}=60V, V_{GS}=0V			1	uA
		V_{DS}=48V, T_J=125°C			50	uA
I_{GSS}	Gate to source leakage current, forward	V_{GS}=20V, V_{DS}=0V			100	nA
	Gate to source leakage current, reverse	V_{GS}=-20V, V_{DS}=0V			-100	nA
On characteristics						
$V_{GS(TH)}$	Gate threshold voltage	V_{DS}=V_{GS}, I_D=250uA	1.4		2	V
$R_{DS(ON)}$	Drain to source on state resistance	V_{GS}=4.5V, I_D=10A,T_J=25°C		12	14.5	mΩ
		V_{GS}=10V, I_D=10A,T_J=25°C		9.5	11.5	mΩ
		V_{GS}=10V, I_D=10A,T_J=125°C		14		mΩ
G_{fs}	Forward transconductance	V_{DS}=5V, I_D=10A		32		S
Dynamic characteristics						
C_{iss}	Input capacitance	V_{GS}=0V, V_{DS}=30V, f=1MHz		1068		pF
C_{oss}	Output capacitance			354		
C_{rss}	Reverse transfer capacitance			13		
$t_{d(on)}$	Turn on delay time	V_{DS}=30V, I_D=10A, R_G=4.7Ω, V_{GS}=10V (note 4,5)		5		ns
t_r	Rising time			34		
$t_{d(off)}$	Turn off delay time			24		
t_f	Fall time			8		
Q_g	Total gate charge	V_{DS}=48V, V_{GS}=10V, I_D=10A , I_G=3mA (note 4,5)		18		nC
Q_{gs}	Gate-source charge			2.2		
Q_{gd}	Gate-drain charge			4		
R_g	Gate resistance	V_{DS}=0V, Scan F mode		1.8		Ω
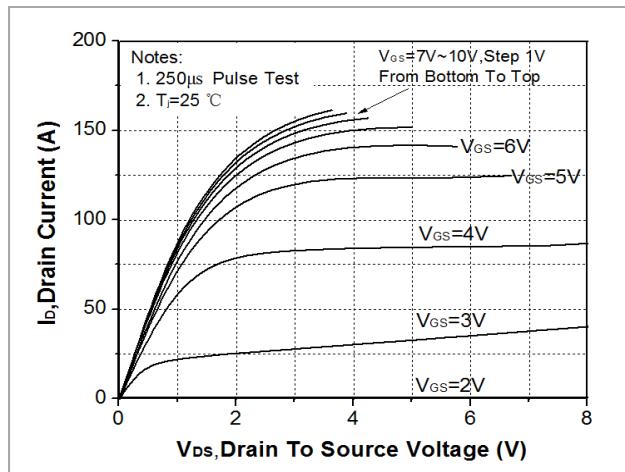
Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_S	Continuous source current	Integral reverse p-n Junction diode in the MOSFET			10	A
I_{SM}	Pulsed source current				40	A
V_{SD}	Diode forward voltage drop.	I_S=10A, V_{GS}=0V			1.4	V
t_{rr}	Reverse recovery time	I_S=10A, V_{GS}=0V, dI_F/dt=100A/us		29		ns
Q_{rr}	Reverse recovery charge			14		nC
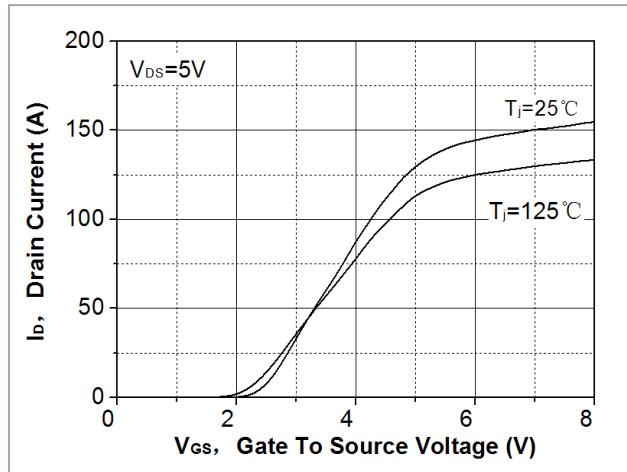
※. Notes
1. Repeatitive rating : pulse width limited by junction temperature.
2. L =0.5mH, I_{AS} =19.5A, V_{DD}=40V, R_G=25Ω, Starting T_J = 25°C
3. I_{SD} ≤10A, di/dt = 100A/us, V_{DD} ≤ BV_{DSS}, Staring T_J =25°C
4. Pulse Test : Pulse Width ≤ 300us, duty cycle ≤ 2%.
5. Essentially independent of operating temperature.
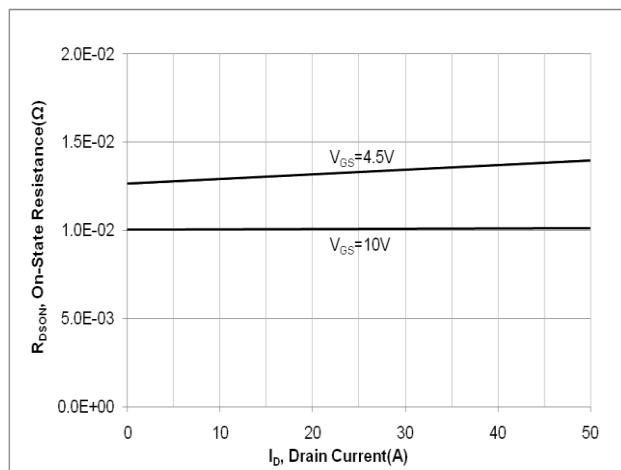
**Fig. 1. On-state characteristics**
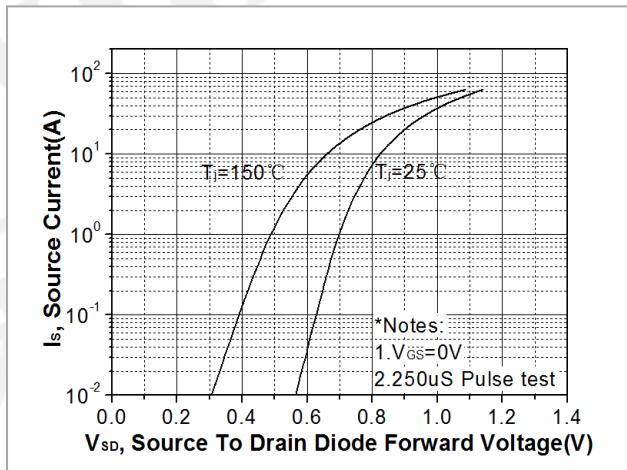

Fig. 2. Transfer Characteristics
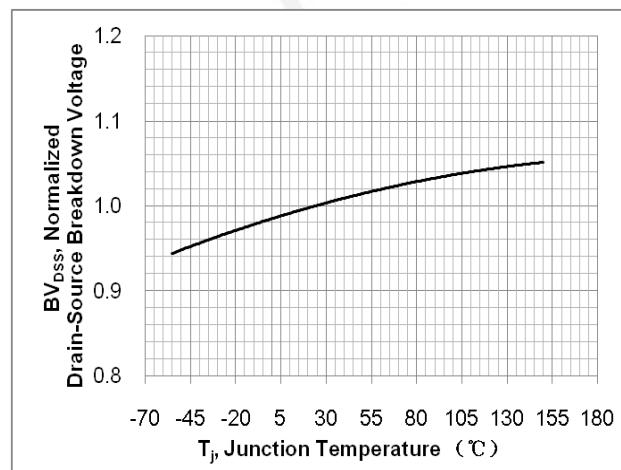
Fig. 3. On-resistance variation vs. drain current and gate voltage
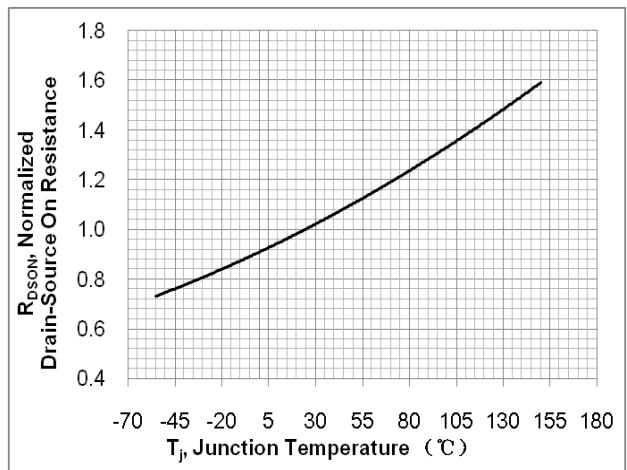

**Fig. 4. On-state current vs. diode forward voltage**
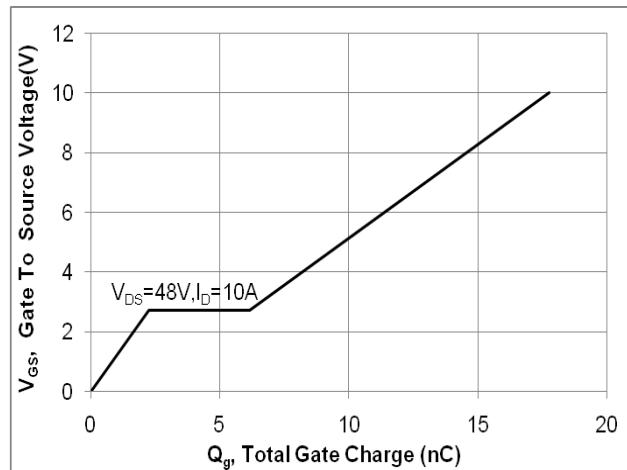
**Fig 5. Breakdown voltage variation vs. junction temperature**
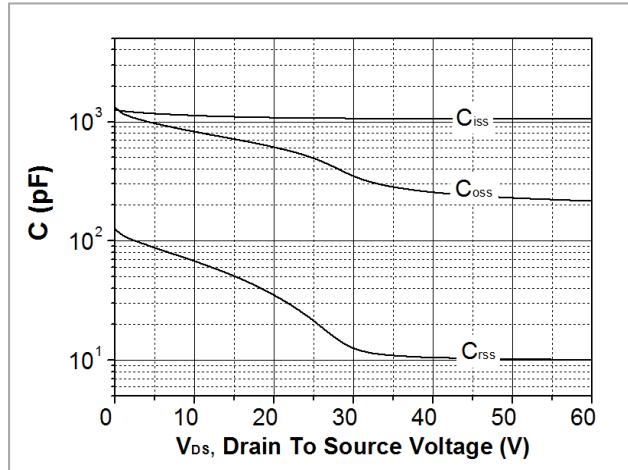
**Fig. 6. On-resistance variation vs. junction temperature**
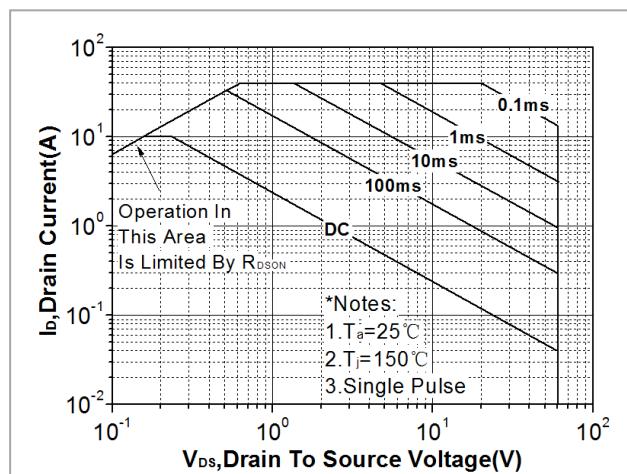
Fig. 7. Gate charge characteristics


Fig. 8. Capacitance Characteristics

Fig. 9. Maximum safe operating area

### Fig. 10. Transient thermal response curve
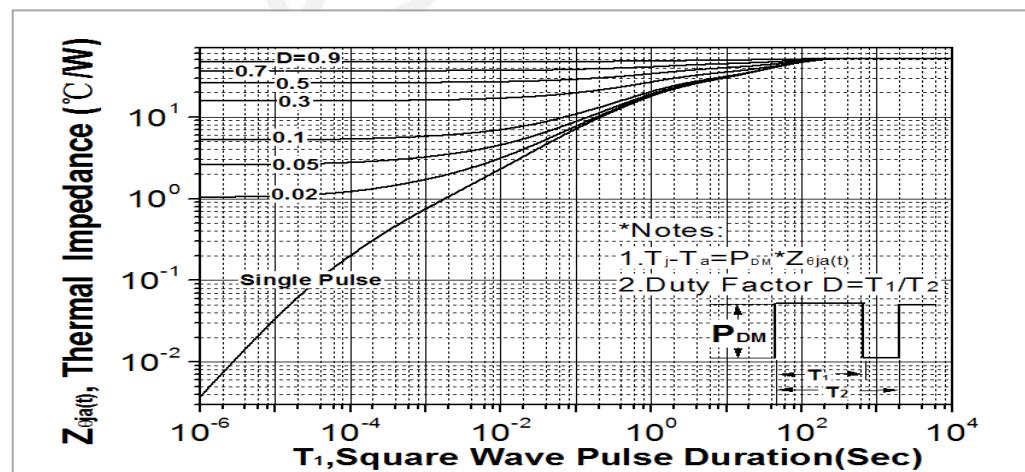
**Fig. 11. Gate charge test circuit & waveform**
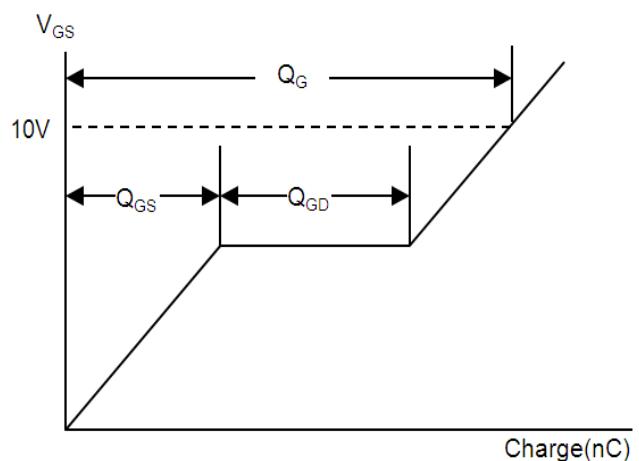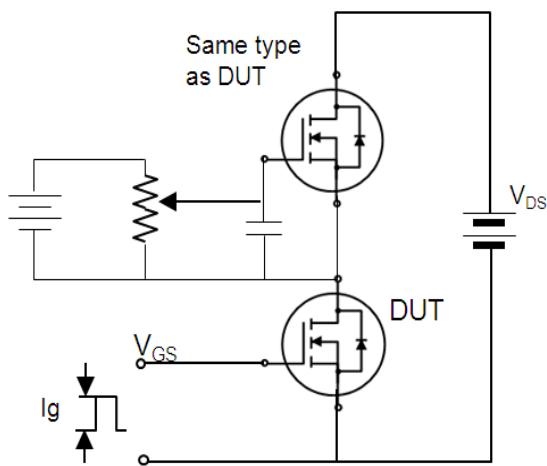

Fig. 12. Switching time test circuit & waveform
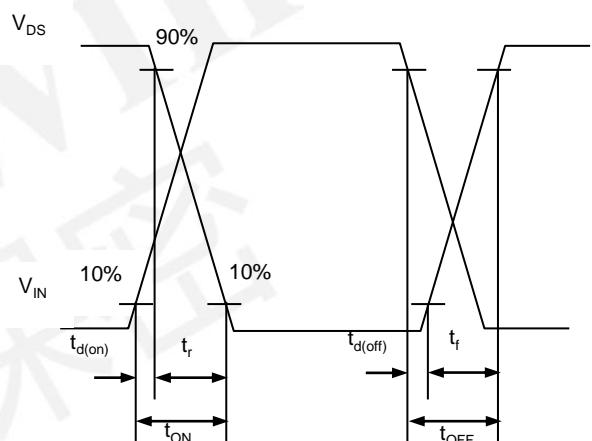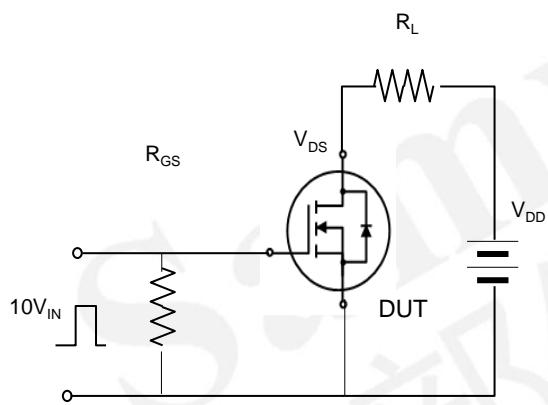
Fig. 13. Unclamped Inductive switching test circuit & waveform

$$E_{AS} = \frac{1}{2} L I_{AS}^2$$

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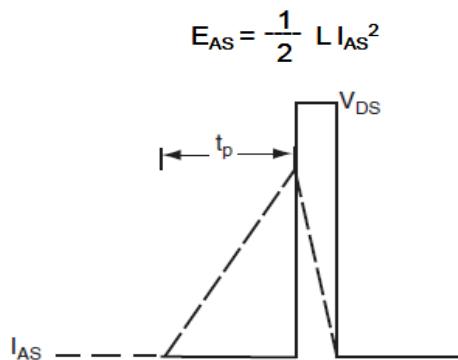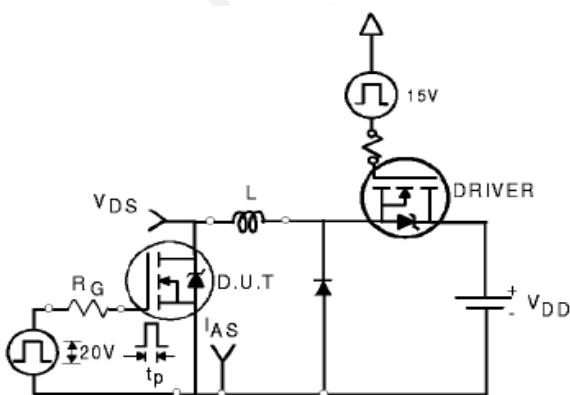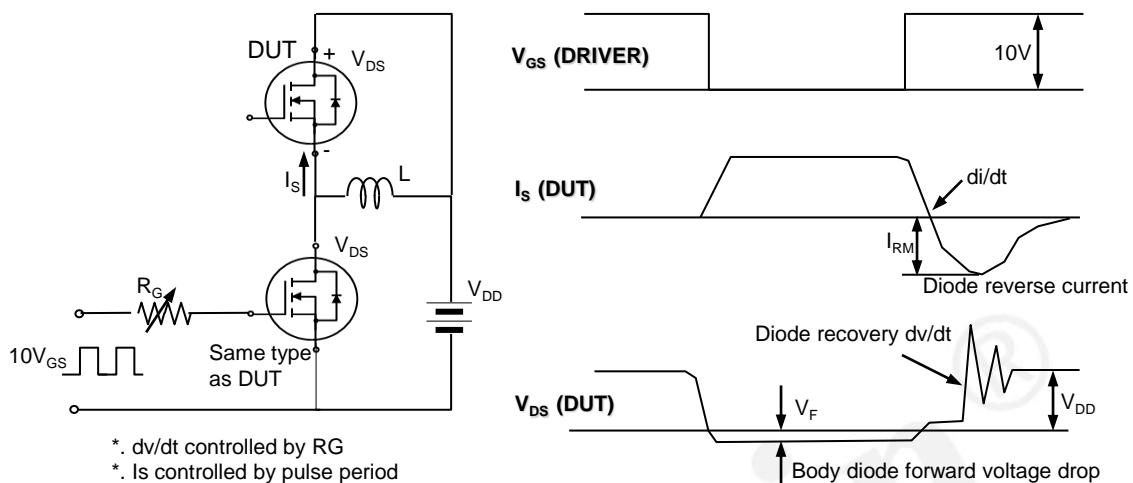
Fig. 14. Peak diode recovery dv/dt test circuit & waveform

*. dv/dt controlled by RG
*. Is controlled by pulse period

DISCLAIMER

* All the data & curve in this document was tested in SEMIPOWER TESTING & APPLICATION CENTER.

* This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.

* Qualification standards can also be found on the Web site (**http://www.semipower.com.cn**) ✉

* Suggestions for improvement are appreciated, Please send your suggestions to **samwin@samwinsemi.com**